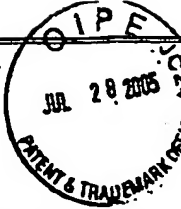


Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICELIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)ATTY. DOCKET NO.
MI22-1897SERIAL NO.
10/050,347APPLICANT
Gurtej S. SandhuFILING DATE
January 15, 2002GROUP
2813

U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>RL</i>	AA	3,627,598	12/71	McDonald et al.	—	—	
	AB	4,254,161	03/81	Kemlage	—	—	
	AC	4,262,631	04/81	Kubacki	—	—	
	AD	4,435,447	03/84	Ito et al.	—	—	
	AE	4,882,649	11/89	Chen et al.	—	—	
	AF	4,891,684	01/90	Nishioka et al.	—	—	
	AG	4,980,307	12/90	Ito et al.	—	—	
	AH	4,996,081	02/91	Ellul et al.	—	—	
	AJ	5,051,794	09/91	Mori	—	—	
<i>RL</i>	AK	5,142,438	08/92	Reinberg et al.	—	—	

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
<i>RL</i>	AK	EP 0886308 A2	12/98	EPO	—	—		
<i>RL</i>	AL	237243 a	04/01	Japan	—	—		
	AM							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

<i>RL</i>	AN	Wolf, Stanley, <i>Silicon Processing for the VLSI Era</i> (1995), V.3, 648-9
<i>RL</i>	AO	Laughery et al., <i>Effect of H₂ Content on Reliability of Ultrathin In-Situ Steam Generated (ISSG) SiO₂</i> , Sept., 2000, Vol. 21, No. 9.
	AP	

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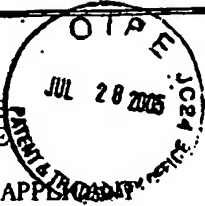




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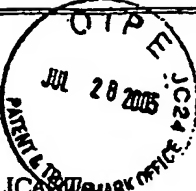



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Form PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)						ATTY. DOCKET NO. M122-1898		SERIAL NO. 10/050,348	
				APPLICANT Gurtej S. Sandhu					
				FILING DATE January 15, 2002		GROUP 2813			
U.S. PATENT DOCUMENTS									
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
	AA	5,498,890	03/96	Kim et al.	—	—			
	AB	5,504,029	04/96	Murata et al.	—	—			
	AC	5,508,542	04/96	Geiss et al.	—	—			
	AD	5,523,596	06/96	Ohi et al.	—	—			
	AE	5,731,235	03/98	Srinivasan et al.	—	—			
	AF	5,821,142	10/98	Sung et al.	—	—			
	AG	5,844,771	12/98	Graettinger et al.	—	—			
	AH	5,851,603	12/98	Tsai et al.	—	—			
	AI	5,882,978	03/99	Srinivasan et al.	—	—			
		AJ	6,001,741	12/99	Alers	—	—		
FOREIGN PATENT DOCUMENTS									
		Document Number	Date	Country	Class	Subclass	Translation		
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	AK								
	AL								
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)									
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	AP								
EXAMINER		DATE CONSIDERED  12/2/05							
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.									

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				FILING DATE January 15, 2002		GROUP 2813	
U.S. PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA	6,001,748	12/99	Tanaka			
	AB	6,008,104	12/99	Schrems			
	AC	6,051,865	04/00	Gardner et al.			
	AD	6,063,713	06/00	Doan			
	AE	6,077,754	06/00	Srinivasan et al.			
	AF	6,096,597	08/00	Tsu et al.			
	AG	6,111,744	08/00	Doan			
	AH	6,168,980	01/01	Yamazaki et al.			
	AI	6,207,985 B1	03/01	Walker			
	AJ	6,323,138 B1	11/01	Doan			
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	AK						
	AL						
	AM						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AN						
	AO						
	AP						
EXAMINER	DATE CONSIDERED						
	12/2/02						
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U.S. PATENT DOCUMENTS									
Examiner Initial	Class	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
	AA	6,348,420 B1	02/02	Raaijmakers et al.					
	AB	6,265,327	07/01	Kobayashi et al.					
	AC	6,350,707 B1	02/02	Liu et al.					
	AD	6,723,599 B2	04/04	Eppich et al.					
	AE	6,893,981 B2	05/05	Park et al.					
	AF	09/653,281	08/00	Beaman et al.					
	AG	2001/0036752	11/01	DeBoer et al.					
	AH	2002/0009861	08/98	Narvankar et al.					
	AI	2002/0052124	05/02	Raaijmakers et al.					
	AJ	2003/0034518A1	02/03	Yoshikawa					
FOREIGN PATENT DOCUMENTS									
		Document Number	Date	Country	Class	Subclass	Translation		
							Yes	No	
	AK								
	AL								
	AM								
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)									
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	AP								
EXAMINER		DATE CONSIDERED  12/2/05							
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					FILING DATE January 15, 2002		GROUP 2813	



U.S. PATENT DOCUMENTS							
Examiner's Initials	Class	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
<i>RL</i>	AA	6,015,739	1/18/00	Gardner et al.			
<i>RL</i>	AB	6,057,854	05/2/00	Gardner et al.			
<i>not considered</i>		6,649,58 B1	11/18/03	Cheng et al.			
<i>RL</i>	AD	2005/0087820 A1	4/28/05	Bai et al.			
<i>RL</i>	AE	2006/0134864 A1	6/22/06	Higashitani et al.			
	AF						
	AG						
	AH						
	AI						

FOREIGN PATENT DOCUMENTS								
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
Examiner's Initials	Class	Document Number	Reference

EXAMINER <i>Walter Schely</i>	DATE CONSIDERED <i>3/1/07</i>
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